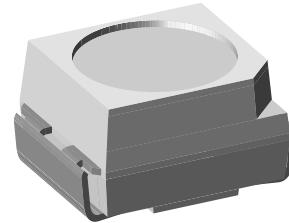


## GaAlAs/GaAlAs Infrared Emitting Diode in SMT Package

### Description

TSMF4710 is a high speed infrared emitting diode in GaAlAs double hetero (DH) technology in a miniature PLCC-2 SMD package.

DH technology combines high speed with high radiant power at wavelength of 870 nm.



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### Features

- High radiant power
- High speed  $t_r = 15$  ns
- High modulation band width  $f_c = 23$  MHz
- Peak wavelength  $\lambda_p = 870$  nm
- High reliability
- Low forward voltage
- Suitable for high pulse current application
- Wide angle of half intensity
- Compatible with automatic placement equipment
- EIA and ICE standard package
- Suitable for infrared, vapor phase and wavesolder process
- 8mm tape and reel standard: GS08 or GS18
- Lead free component

### Applications

- High speed IR data transmission
- High power emitter for low space applications
- High performance transmissive or reflective sensors

### Parts Table

Part	Ordering code	Remarks
TSMF4710	TSMF4710-GS08	MOQ: 7500 pc (5 reels)
TSMF4710	TSMF4710-GS18	MOQ: 8000 pc (1 reel)

### Absolute Maximum Ratings

$T_{amb} = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Test condition	Symbol	Value	Unit
Reverse Voltage		$V_R$	5	V
Forward current		$I_F$	100	mA
Peak Forward Current	$t_p/T = 0.5$ , $t_p = 100$ $\mu\text{s}$	$I_{FM}$	200	mA
Surge Forward Current	$t_p = 100$ $\mu\text{s}$	$I_{FSM}$	1	A
Power Dissipation		$P_V$	170	mW
Junction Temperature		$T_j$	100	$^\circ\text{C}$
Operating Temperature Range		$T_{amb}$	- 40 to + 85	$^\circ\text{C}$

Parameter	Test condition	Symbol	Value	Unit
Storage Temperature Range		$T_{stg}$	- 40 to + 100	°C
Soldering Temperature	$t \leq 10$ sec	$T_{sd}$	260	°C
Thermal Resistance Junction/Ambient		$R_{thJA}$	450	K/W

## Electrical Characteristics

$T_{amb} = 25$  °C, unless otherwise specified

Parameter	Test condition	Symbol	Min	Typ.	Max	Unit
Forward Voltage	$I_F = 100$ mA, $t_p = 20$ ms	$V_F$		1.5	1.8	V
	$I_F = 1$ A, $t_p = 100$ $\mu$ s	$V_F$		2.3		V
Temp. Coefficient of $V_F$	$I_F = 100$ mA	$TK_{V_F}$		-2.1		mV/K
Reverse Current	$V_R = 5$ V	$I_R$			10	$\mu$ A
Junction capacitance	$V_R = 0$ V, $f = 1$ MHz, $E = 0$	$C_j$		125		pF

## Optical Characteristics

$T_{amb} = 25$  °C, unless otherwise specified

Parameter	Test condition	Symbol	Min	Typ.	Max	Unit
Radiant Intensity	$I_F = 100$ mA, $t_p = 20$ ms	$I_e$		10	22	mW/sr
	$I_F = 1$ A, $t_p = 100$ $\mu$ s	$I_e$		100		mW/sr
Radiant Power	$I_F = 100$ mA, $t_p = 20$ ms	$\phi_e$		40		mW
Temp. Coefficient of $\phi_e$	$I_F = 100$ mA	$TK_{\phi_e}$		-0.35		%/K
Angle of Half Intensity		$\phi$		$\pm 60$		deg
Peak Wavelength	$I_F = 100$ mA	$\lambda_p$		870		nm
Spectral Bandwidth	$I_F = 100$ mA	$\Delta\lambda$		40		nm
Temp. Coefficient of $\lambda_p$	$I_F = 100$ mA	$TK_{\lambda_p}$		0.25		nm/K
Rise Time	$I_F = 100$ mA	$t_r$		15		ns
Fall Time	$I_F = 100$ mA	$t_f$		15		ns
Virtual Source Size		$\emptyset$		0.44		mm

## Typical Characteristics ( $T_{amb} = 25$ °C unless otherwise specified)

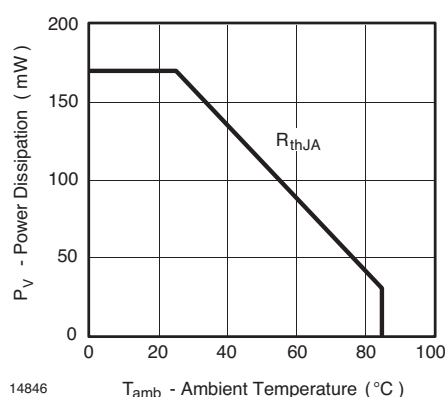


Figure 1. Power Dissipation vs. Ambient Temperature

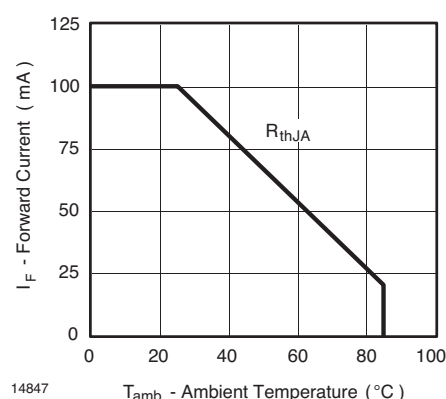


Figure 2. Forward Current vs. Ambient Temperature

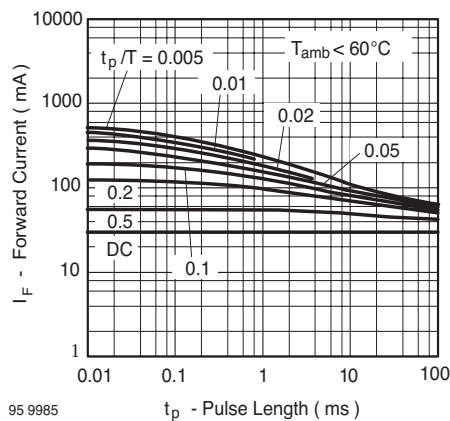


Figure 3. Pulse Forward Current vs. Pulse Duration

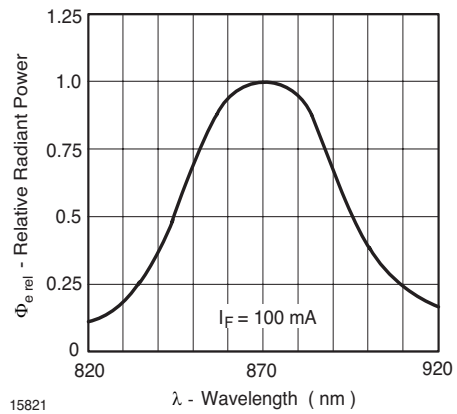


Figure 6. Relative Radiant Power vs. Wavelength

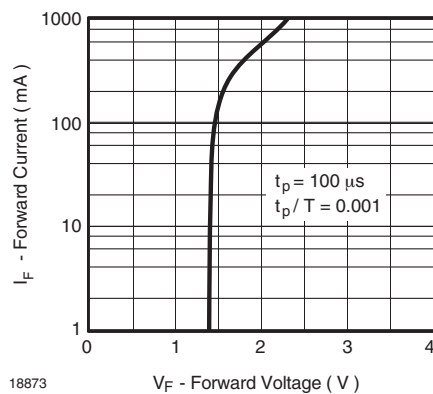


Figure 4. Forward Current vs. Forward Voltage

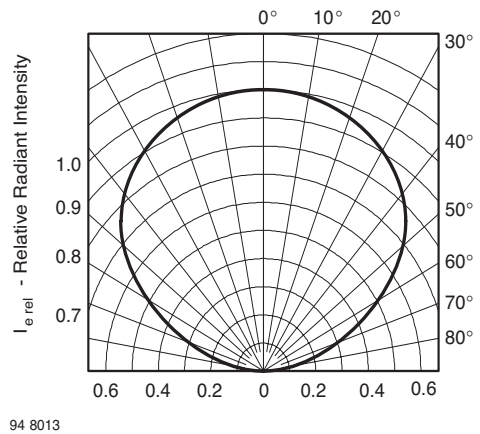


Figure 7. Relative Radiant Intensity vs. Angular Displacement

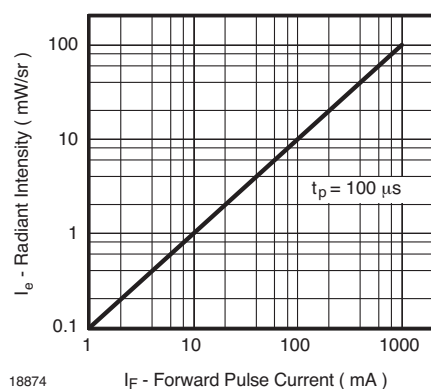
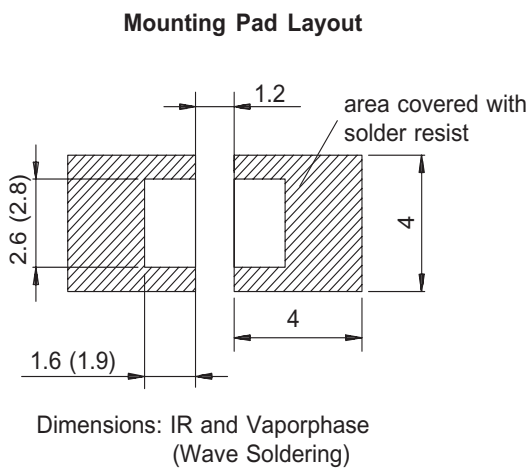
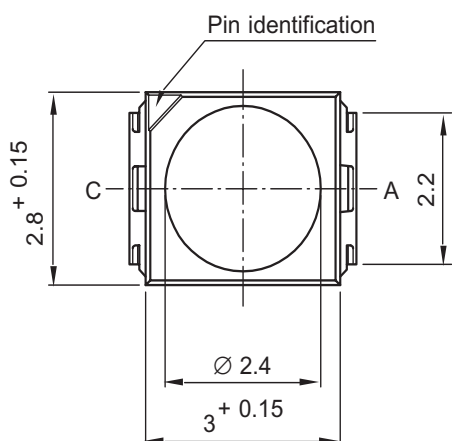
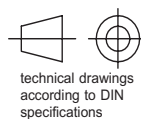
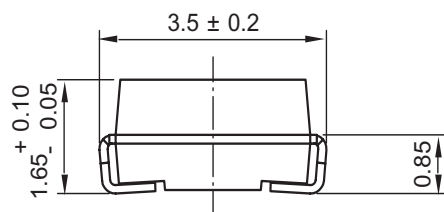


Figure 5. Radiant Intensity vs. Forward Pulse Current

## Package Dimensions in mm



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## Temperature - Time Profile

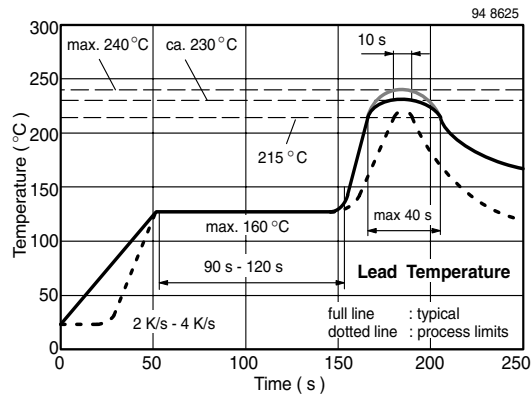


Figure 8. Infrared Reflow Soldering Optodevices (SMD Package)

## Drypack

Devices are packed in moisture barrier bags (MBB) to prevent the products from moisture absorption during transportation and storage. Each bag contains a desiccant.

## Floor Life

Floor life (time between soldering and removing from MBB) must not exceed the time indicated in J-STD-020. TSM... is released for:

Moisture Sensitivity Level 2, according to JEDEC, J-STD-020

Floor Life: 1 year

Conditions:  $T_{amb} < 30\text{ }^{\circ}\text{C}$ ,  $RH < 60\%$

## Drying

In case of moisture absorption devices should be baked before soldering. Conditions see J-STD-020 or Label. Devices taped on reel dry using recommended conditions 192 h @  $40\text{ }^{\circ}\text{C}$  (+  $5\text{ }^{\circ}\text{C}$ ),  $RH < 5\%$

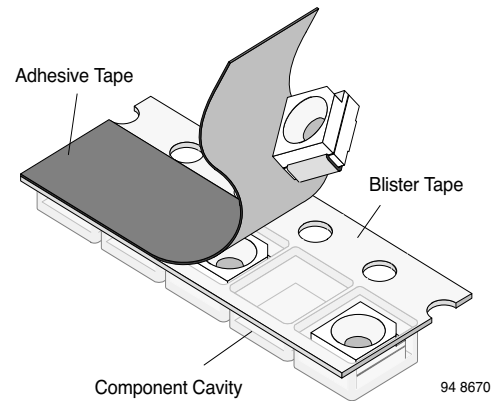


Figure 9. Blister Tape

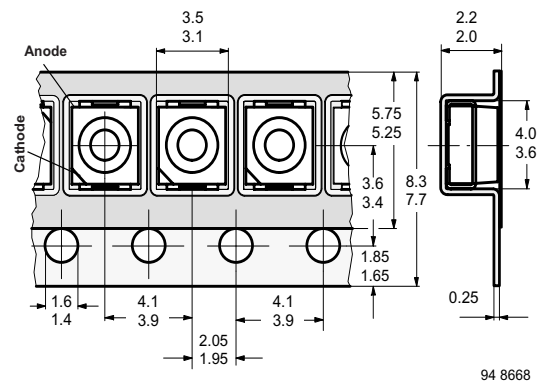


Figure 10. Tape Dimensions in mm for PLCC-2

## Missing Devices

A maximum of 0.5 % of the total number of components per reel may be missing, exclusively missing components at the beginning and at the end of the reel. A maximum of three consecutive components may be missing, provided this gap is followed by six consecutive components.

## Cover Tape Removal Force

The removal force lies between 0.1 N and 1.0 N at a removal speed of 5 mm/s. In order to prevent components from popping out of the blisters, the cover tape must be pulled off at an angle of 180 ° with regard to the feed direction.

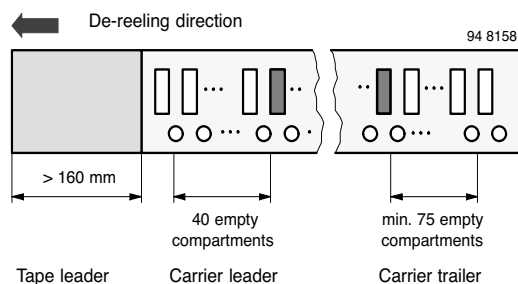


Figure 11. Beginning and End of Reel

The tape leader is at least 160 mm and is followed by a carrier tape leader with at least 40 empty compartments. The tape leader may include the carrier tape as long as the cover tape is not connected to the carrier tape. The least component is followed by a carrier tape trailer with a least 75 empty compartments and sealed with cover tape.

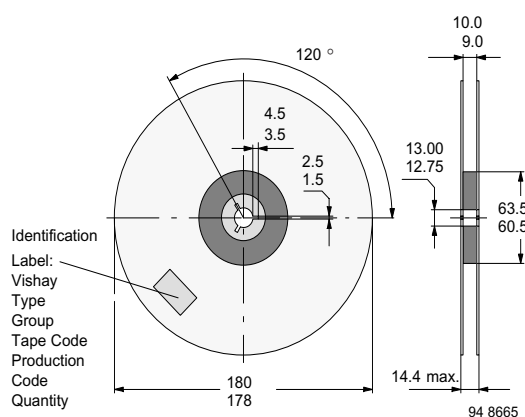


Figure 12. Dimensions of Reel

## **Ozone Depleting Substances Policy Statement**

It is the policy of **Vishay Semiconductor GmbH** to

1. Meet all present and future national and international statutory requirements.
2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

It is particular concern to control or eliminate releases of those substances into the atmosphere which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) intend to severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

**Vishay Semiconductor GmbH** has been able to use its policy of continuous improvements to eliminate the use of ODSs listed in the following documents.

1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively
2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA
3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

**Vishay Semiconductor GmbH** can certify that our semiconductors are not manufactured with ozone depleting substances and do not contain such substances.

### **We reserve the right to make changes to improve technical design and may do so without further notice.**

Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use Vishay Semiconductors products for any unintended or unauthorized application, the buyer shall indemnify Vishay Semiconductors against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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